



**INDIAN INSTITUTE OF SCIENCE EDUCATION AND
RESEARCH THIRUVANANTHAPURAM [IISERTVM]**

PH.-0471 2778019,
EMAIL: purchasestores@iisertvm.ac.in

MARUTHAMALA.P.O VITHURA. P.O
THIRUVANANTHAPURAM 695551,
KERALA, INDIA
GST No.32AAAJI0299R1ZS

IISER/PUR/1868/SG/SDS/25-26

03.02.2026

CORRIGENDUM

Sub: Supply, installation and commissioning of Field Emission Scanning Electron Microscope (FE-SEM) : reg

Ref: Tender ID: 2026_IISRT_893689_1

1. The changes in the technical specifications are added as corrigendum to the above mentioned tender. The changes are placed at Annexure 1.
2. All other Terms and Conditions remain the same. Bidders may quote accordingly

Thanking You,

Yours Faithfully


Assistant Registrar (P&S)

Annexure 1 to corrigendum

Modifications to the specifications based on the corrigendum received.

Sl. No.	Feature	Original Specification	Modified Specification
2	Resolution (HV)	≤ 1.0 nm at 15 kV; ≤ 3.0 nm at 1-3 kV or better.	< 1.0 nm at 15 kV or more; ≤ 3.0 nm at 1-3 kV or better. Furthermore, the vendor has to submit published articles in internationally peer-reviewed journals in support of their quoted FESEM system that is used to study the geological samples (for example, silicate minerals, carbonates, halides, etc.) and perform EBSD and EDS analysis as quoted elsewhere (Specification Item No. 13 and 14) in Annexure I. These articles have to justify the quoted resolution.
6	Probe current	≤ 10 pA to ≥ 200 nA or higher.	≤ 10 pA to ≥ 100 nA or higher. The vendor has to submit published articles in internationally peer-reviewed journals in support of their quoted FESEM system that is used to study the geological samples (for example, silicate minerals, carbonates, halides, etc.) and perform EBSD and EDS analysis as quoted elsewhere (Specification Item Nos. 13 and 14) in Annexure I. These articles have to justify the quoted Probe Current values.
7	Operating Modes	High vacuum, low vacuum/variable pressure up to ≥ 130 Pa or better. The vendor should clearly verify whether their instrument allows non-conductive geological rock samples to be analyzed using EBSD without coating the polished surface, under their operating conditions.	High vacuum, low vacuum/variable pressure up to ≥ 130 Pa. The vendor should clearly demonstrate whether their instrument allows non-conductive geological rock samples to be analyzed using EBSD without coating the polished surface, under their operating conditions.
9	Detectors	Secondary Electron (SE) detector, multi-segment Back-Scattered Electron (BSE) detector, LV-SE. Detectors capable of forming a composition image or equivalent, including surficial topographic images or equivalent. BSE should work for the entire working distance and should be capable of working both in HV and LV operating modes. In-lens/In-column SE should be a part of the system.	Secondary Electron (SE) detector, multi-segment Back-Scattered Electron (BSE) detector, LV-SE. Detectors capable of forming a composition image or equivalent, including surficial topographic images or equivalent. BSE should work for the entire working distance and should be capable of working both in HV and LV operating modes. In-lens/In-column SE should be a part of the system. In case, In-lens/In-column SE is not part of the quoted FESEM system, then the vendor has to demonstrate that their system is capable of performing High Angular Resolution EBSD as mentioned under the Specification Nos. 14, 16, and 18 in Annexure I.

[Handwritten signature]
3/2/26